

## Motivation

- ▶ Given a database of images indexed by a large DL model
- ▶ Queries from small network (e.g. working on a mobile device)
- ▶ Re-index the whole database by the small model for it to match?
- ▶ Or: can the small model learn to directly map queries like the large model

## Contributions

- ▶ Knowledge transfer for pair-based metric learning for instance-level image retrieval
- ▶ Introduction of asymmetric metric learning paradigm
- ▶ **Asymmetric testing**: database represented by large network, queries by lightweight network on device, no re-indexing

## Metric learning

- ▶ *Cosine similarity* is used in this work
- ▶ The *symmetric similarity*  $s_{\theta}^{\text{sym}}(a, x)$  between an anchor  $a \in X$  and a positive or negative example  $x \in P(a) \cup N(a)$  is obtained by representing both in the feature space of the student  $f_{\theta}$ :

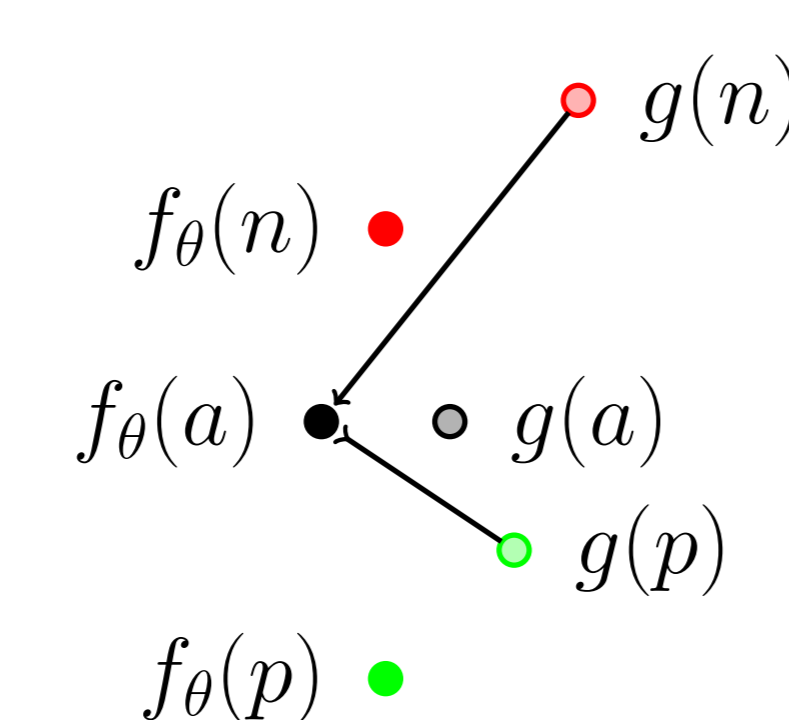
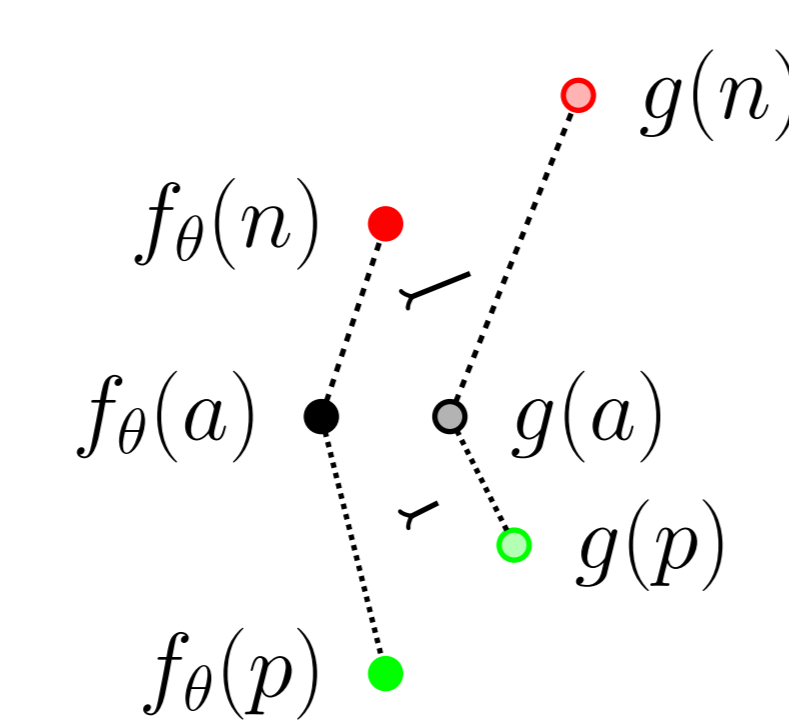
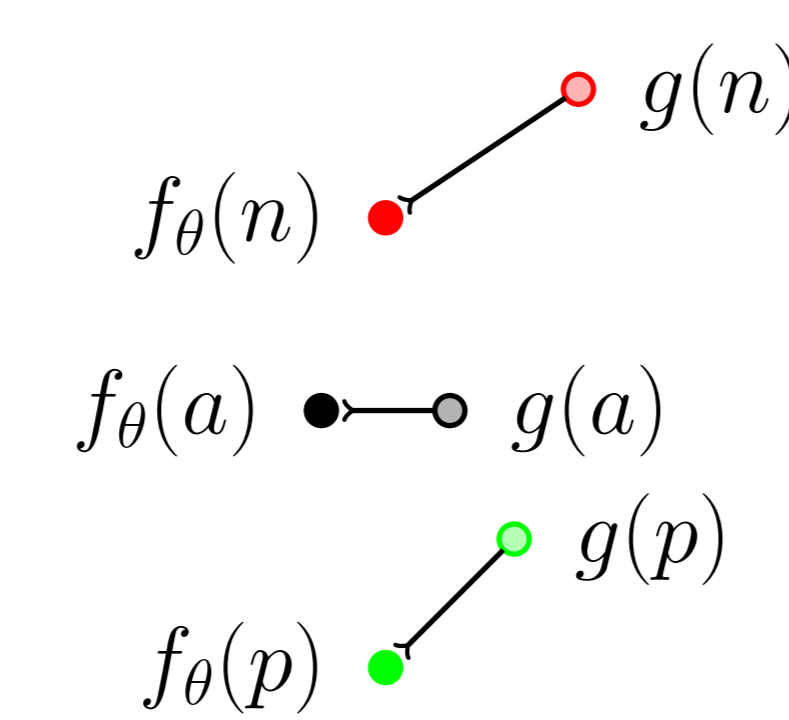
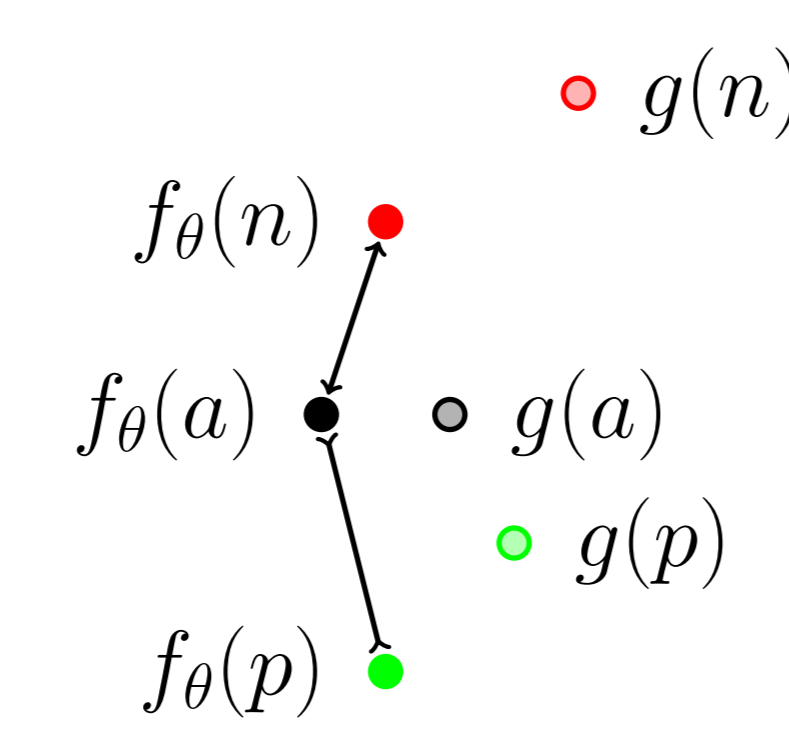
$$s_{\theta}^{\text{sym}}(a, x) := \text{sim}(f_{\theta}(a), f_{\theta}(x)).$$

- ▶ This is a standard setting for metric learning
- ▶ Symmetric testing is based on this similarity

## Asymmetric metric learning (AML)

- ▶ Instance-level image retrieval
  - ▶ Applies to both symmetric and asymmetric testing
  - ▶ Combines **knowledge transfer** with **supervised metric learning**
  - ▶ In *asymmetric similarity*  $s_{\theta}^{\text{asym}}(a, x)$  the anchor  $a$  is represented by the student  $f_{\theta}$ , while positive and negative examples  $x$  are represented by the teacher  $g$ :
- $$s_{\theta}^{\text{asym}}(a, x) := \text{sim}(f_{\theta}(a), g(x))$$
- ▶ Can be used with any supervised metric learning loss

## Metric learning and knowledge transfer



### Symmetric

- labels used, teacher not used ( $f_{\theta}$ : student,  $g$ : teacher)
- **positive** pairs mutually **attract** and **negative** pairs **repulse** in student space
- losses: Contr, Triplet, MS [6]

### Regression

- labels not used, teacher used
- examples in **student space** attracted to same examples in **teacher space**
- loss: Reg

### Relational

- labels not used, teacher used
- pairwise relations encouraged to be **compatible in both spaces**
- losses: RKD [2], DR [1]

### Asymmetric

- both labels and teacher used
- **positives** attract, **negatives** repulse using asymmetric similarity
- losses: any supervised losses

## Best loss functions

- ▶ Regression (Reg)

$$\ell_R(a; \theta) := -s_{\theta}^{\text{asym}}(a, a) = -\text{sim}(f_{\theta}(a), g(a))$$

- ▶ Asymmetric contrastive (Contr)

$$\ell_C(a; \theta) := \sum_{n \in N(a)} [s_{\theta}^{\text{asym}}(a, n) - m]_+ - \sum_{p \in P(a)} s_{\theta}^{\text{asym}}(a, p)$$

- ▶ Asymmetric contrastive + regression (Contr<sup>+</sup>)

$$\ell_{C^+}(a; \theta) := \sum_{n \in N(a)} [s_{\theta}^{\text{asym}}(a, n) - m]_+ - \sum_{p \in P(a)} s_{\theta}^{\text{asym}}(a, p) - s_{\theta}^{\text{asym}}(a, a)$$

## Experimental setup

- ▶ Training set: SfM120k [4]
  - ▶ Positives: based on closest camera position to query and number of inliers
  - ▶ Negatives:  $k$ -nearest neighbours from non-matching clusters
- ▶ Test sets: revisited Oxford and Paris [3] (including results with 1M distractors)

NETWORK	TEACHER	$d$	GFLOPS	PARAM(M)
ResNet101		2048	42.85	42.50
EfficientNet-B3		1536	5.36	10.70
	ResNet101	2048	6.26	13.84

- ▶ **teacher**: ResNet101 (RN101)
- ▶ **student**: EfficientNet-B3[5] (EN-B3),  $7 \times$  less FLOPS and  $3 \times$  less parameters

## Symmetric testing

STU	$d$	TEA	LAB	MINING	ASYM	LOSS	MEDIUM		HARD					
							ROxf	RPar	ROxf	RPar				
RN101	2048		✓	hard		Contr	65.4	76.7	40.1	55.2				
EN-B3	512		✓	hard		Contr	53.8	70.9	26.2	46.0				
							2048	✓	hard	Contr	59.6	75.1	33.3	51.9
EN-B3	2048	RN101	✓	hard	✓	Contr <sup>+</sup>	66.8	77.1	42.5	55.5				
							✓	hard	✓	Contr	66.3	77.4	41.3	55.5
							✓	hard	✓	Triplet	39.5	69.4	11.6	45.8
							✓	hard	✓	MS	39.9	69.7	11.7	46.2
							–	✓	Reg	64.9	74.4	40.5	52.4	
							random		RKD	56.3	73.0	30.5	50.4	
	random		DR	40.3	69.9	11.8	46.4							

- ▶ Performance measured by mAP
- ▶ **Contr** and **Contr<sup>+</sup>**: student beats teacher
- ▶ **Reg**: second best, slightly below teacher
- ▶ Everything else worse than student alone

## Asymmetric testing

STU	$d$	TEA	LAB	MINING	ASYM	LOSS	MEDIUM		HARD					
							ROxf	RPar	ROxf	RPar				
RN101	2048		✓	hard		Contr	65.4	76.7	40.1	55.2				
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							2048	✓	hard	Contr	59.6	75.1	33.3	51.9
EN-B3	2048	RN101	✓	hard	✓	Contr <sup>+</sup>	45.2	63.7	19.6	40.9				
							✓	hard	✓	Contr	37.4	57.4	10.9	33.7
							✓	hard	✓	Triplet	1.5	4.0	0.7	2.5
							✓	hard	✓	MS	1.5	4.0	0.7	2.4
							–	✓	Reg	52.9	65.2	27.8	42.4	
							random		RKD	1.6	3.8	0.7	2.4	
	random		DR	1.5	4.0	0.7	2.5							

- ▶ **Reg**: best, but significantly lower than student alone
- ▶ **Contr<sup>+</sup>/ Contr**: second / third best, significantly lower than Reg
- ▶ **RKD, DR**: completely fail (expected, absolute coordinates needed)
- ▶ **Triplet, MS**: completely fail (unexpected)

## References

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